

Special Issue

Advanced Optoelectronic Detection Technologies and Systems

Message from the Guest Editors

It is our pleasure to announce a new Special Issue of *Applied Sciences* devoted to advanced optoelectronic detection technologies and systems. It will cover both the theoretical and experimental advances of materials, devices, algorithms, and systems in optoelectronic detection technology. Particularly welcome will be works focused on semiconductor, spintronic, magnetic, and terahertz devices, and their applications in sensors and detections. Taking into account that a validation of a supposition is usually realized via a cross-check, the use of combined approaches are also welcomed. This Special Issue also collects the selected papers from Symposium on Semiconductor Light Source System 2023 organized by the China Electrotechnical Society.

Guest Editors

Prof. Dr. Pingjuan Niu

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Dr. Xiuyan Li

Dr. Jia Shi

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Deadline for manuscript submissions

closed (31 October 2024)



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About the Journal

Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

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